

FDH44N50

44A, 500V, 0.12 Ohm, N-Channel SMPS Power MOSFET

Applications

Switch Mode Power Supplies(SMPS), such as

- PFC Boost
- Two-Switch Forward Converter
- Single Switch Forward Converter
- Flyback Converter
- Buck Converter
- · High Speed Switching

Features

- \bullet Low Gate Charge ${\bf Q}_{\bf g}$ results in Simple Drive Requirement
- Improved Gate, Avalanche and High Reapplied dv/dt Ruggedness
- Reduced r_{DS(ON)}
- Reduced Miller Capacitance and Low Input Capacitance
- · Improved Switching Speed with Low EMI
- 175°C Rated Junction Temperature

Package JEDEC TO-247 SOURCE DRAIN GATE DRAIN (FLANGE)

Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DSS}	Drain to Source Voltage	500	V
V _{GS}	Gate to Source Voltage	±30	V
	Drain Current		
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$)	44	Α
I _D	Continuous ($T_C = 100^{\circ}C$, $V_{GS} = 10V$)	32	Α
	Pulsed ¹	176	Α
D	Power dissipation	750	W
P_{D}	Derate above 25°C	5	W/ºC
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C
	Soldering Temperature for 10 seconds	300 (1.6mm from case)	°C
	Mounting Torque, 8-32 or M3 Screw	10ibf*in (1.1N*m)	

Thermal Characteristics

$R_{ heta JC}$	Thermal Resistance Junction to Case	0.2	°C/W
$R_{\theta CS}$	Thermal Resistance Case to Sink, Flat, Greased Surface	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	40	oC/W

	Package	Marking	and	Orderina	Information
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Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDH44N50	FDH44N50	TO-247	-	-	30

Electrical Characteristics $T_J = 25$ °C (unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Statics						
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	500	-	-	V
$\Delta B_{VDSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	Reference to 25°C, ID = 1mA	-	0.61	-	V/°C
r _{DS(ON)}	Drain to Source On-Resistance	$V_{GS} = 10V, I_D = 22A$	-	0.11	0.12	Ω
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3.15	4	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 500V$ $T_{C} = 25$ $V_{GS} = 0V$ $T_{C} = 15$		-	25 250	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	-	-	±100	nA

Dynamics

			-99			
9 _{fs}	Forward Transconductance	$V_{DS} = 50V, I_{D} = 22A$	11	-	-	S
Q _{g(TOT)}	Total Gate Charge at 10V	V _{GS} = 10V,	- 10	90	108	nC
Q _{gs}	Gate to Source Gate Charge	$V_{DS} = 400V$	37	24	29	nC
Q _{gd}	Gate to Drain "Miller" Charge	$I_D = 44A$		31	37	nC
t _{d(ON)}	Turn-On Delay Time	$V_{DD} = 250V,$	-	16	-	ns
t _r	Rise Time	$I_{D} = 44A$,	-	84	-	ns
t _{d(OFF)}	Turn-Off Delay Time	$R_G = 2.15\Omega$	-	45	-	ns
t _f	Fall Time	$R_D = 5.68\Omega$	-	79	-	ns
C _{ISS}	Input Capacitance	25// // 27/	-	5335	-	pF
C _{OSS}	Output Capacitance	V _{DS} = 25V, V _{GS} = 0V, If = 1MHz	-	645	-	pF
C _{RSS}	Reverse Transfer Capacitance	1 - 1111112	-	40	-	pF

Avalanche Characteristics

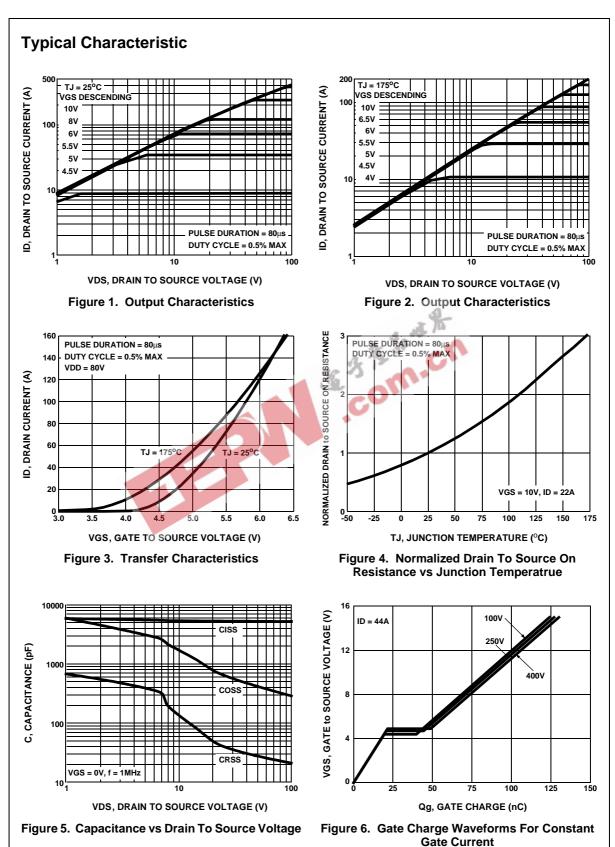
E _{AS}	Single Pulse Avalanche Energy ²	1500	-	-	mJ
I _{AR}	Avalanche Current	-	-	44	Α

Drain-Source Diode Characteristics

I _S	Continuous Source Current (Body Diode)	MOSFET symbol showing the	-	-	44	Α
I _{SM}	Pulsed Source Current ¹ (Body Diode)	integral reverse p-n junction diode.	-	-	176	А
V_{SD}	Source to Drain Diode Voltage	I _{SD} = 44A	ı	0.900	1.2	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 44A$, $dI_{SD}/dt = 100A/\mu s$	-	920	1100	ns
Q_{RR}	Reverse Recovered Charge	$I_{SD} = 44A$, $dI_{SD}/dt = 100A/\mu s$	ı	14	18	μС

Notes:

1: Repetitive rating; pulse width limited by maximum junction temperature
2: Starting T_J = 25°C, L = 1.61mH, I_{AS} = 44



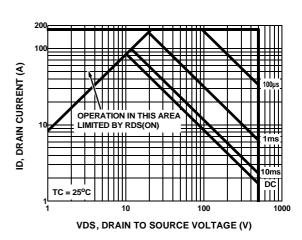


Figure 8. Maximum Safe Operating Area

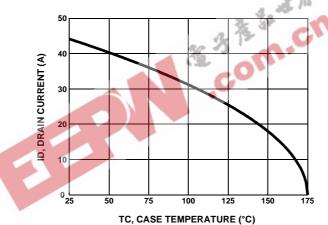
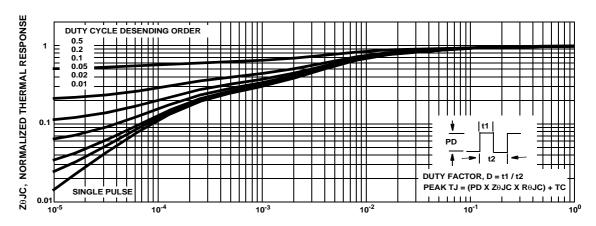


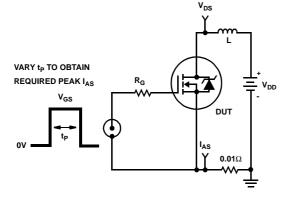
Figure 9. Maximum Drain Current vs Case Temperature



t1, RECTANGULAR PULSE DURATION (S)

Figure 10. Normalized Transient Thermal Impedance, Junction to Case

Test Circuits and Waveforms



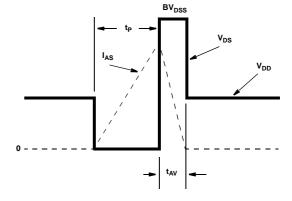


Figure 11. Unclamped Energy Test Circuit

Figure 12. Unclamped Energy Waveforms

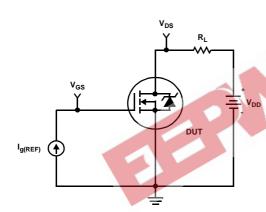


Figure 13. Gate Charge Test Circuit

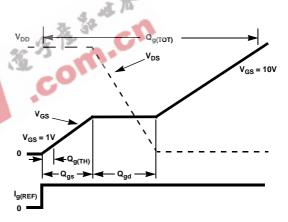


Figure 14. Gate Charge Waveforms

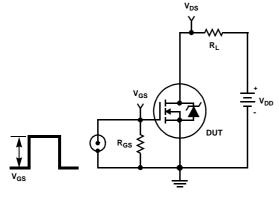


Figure 15. Switching Time Test Circuit

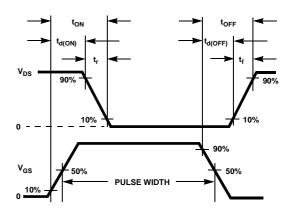


Figure 16. Switching Time Waveform

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